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Formation of CH($A^2\Delta, B^2\Sigma^-, C^2\Sigma^+$) by electron-ion recombination processes in the argon and krypton afterglow reactions of CH₄

Masaharu Tsuji, Kazunari Kobara^{a)}, Hiroyuki Kouno, Hiroshi Obase^{b)} and Yukio Nishimura

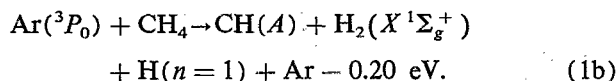
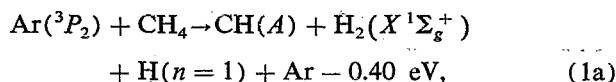
Institute of Advanced Material Study and Department of Molecular Science and Technology, Graduate School of Engineering Sciences, Kyushu University, Kasuga-shi, Fukuoka 816, Japan

(Received 23 July 1990; accepted 3 October 1990)

The CH($A-X, B-X, C-X$) emission systems have been observed from the Ar and Kr afterglow reactions of CH₄. A significant attenuation of the CH($A-X, B-X, C-X$) emissions by an addition of SF₆ into the discharge flow suggested that the CH(A, B, C) radicals are excited via secondary electron-ion recombination processes. Since the CH($A-X, B-X, C-X$) emissions disappeared by trapping ionic active species in the discharge flow, the responsible active species for the CH(A, B, C) production were found to be Ar⁺ and/or (Ar⁺)^{*} in the Ar flow and Kr⁺ and/or (Kr⁺)^{*} in the Kr flow. The contribution of Ar⁺ and Kr⁺ was examined in the He afterglow, where Ar⁺ or Kr⁺ and slow electrons were simultaneously produced by the He(2^3S)/Ar, Kr Penning ionization. Although intense CH($A-X, B-X, C-X$) emissions were observed from Ar⁺/CH₄ where CH_{*n*}⁺ ($n = 2-4$) were formed, they were absent from Kr⁺/CH₄ where only CH₄⁺ was produced. It was, therefore, concluded that CH₂⁺ and/or CH₃⁺ are important precursor ions for the CH(A, B, C) production. The intensity distribution of CH(A, B, C) and the CH(A, B) rovibrational distributions obtained in the Ar afterglow agreed with those through Ar⁺/CH₄, indicating that Ar⁺/CH₄ plays a significant role for the production of precursor ions in the Ar afterglow or (Ar⁺)^{*}/CH₄ provides the same precursor ions. Since the relative intensity of CH(A, B) and the rovibrational distributions of CH(A) in the Kr afterglow were different from those in the Ar afterglow, different electron-ion recombination processes dominantly take part in the CH(A, B) production.

1. INTRODUCTION

Prince *et al.*,¹ and Suzuki and Kuchitsu² observed the CH($A^2\Delta-X^2\Pi_r$) emission system in the Ar afterglow reaction of CH₄. Both groups used a microwave discharge for the generation of Ar active species. Although the former assumed the excitation source to be Ar($^3P_{2,0}$), the latter pointed out that the formation of CH(A) from the Ar($^3P_{2,0}$)/CH₄ reaction is energetically inaccessible:



Suzuki and Kuchitsu² found that ionic species were responsible for the CH(A) production because the emission intensity decreased rapidly by an application of a negative potential to an ion-collector grid placed between the discharge section and the reaction zone. The responsible active species were predicted to be metastable ions (Ar⁺)^{*}, because the Ar pressure dependence of CH($A-X$) was similar to that of Cl^{*} from the (Ar⁺)^{*}/HCl reaction³ and Kr^{*} from the (Ar⁺)^{*}/Kr reaction.⁴ Suzuki and Kuchitsu² estimated the

vibrational and rotational distributions of CH(A) to be $N_0(T_0): N_1(T_1): N_2(T_2) = 100(T_0 = 3000 \pm 1500 \text{ K}): 56(T_1 = 1700 \pm 500 \text{ K}): 10(T_2 = 1000 \text{ K})$ from a spectral simulation. In addition to CH($A-X$), the CH($B^2\Sigma^- - X^2\Pi_r$) emission system was found in the Ar afterglow reaction of CH₄ by Suzuki and Kuchitsu.² However, the intensity ratio of CH($B-X$)/CH($A-X$) and the rovibrational distribution of CH(B) have not been determined. Although electron-ion recombination processes often take part in the formation of neutral excited species in the flowing afterglow (FA), their contribution has not been examined in the previous FA experiments for the CH(A, B) production from the Ar afterglow reaction of CH₄.^{1,2}

In the present study, the CH($A-X, B-X, C-X$) emission systems are observed from reactions of ionic active species with CH₄ in the Ar and Kr afterglows. The disappearance of CH($A-X, B-X, C-X$) by an addition of SF₆ into the discharge flow indicates that all of CH(A, B, C) are formed via secondary electron-ion recombination processes, where precursor ions are produced by the reactions with rare gas ions in the ground states (Ar⁺, Kr⁺) and/or in the metastable states [(Ar⁺)^{*}, (Kr⁺)^{*}]. In order to determine the contribution of Ar⁺ and Kr⁺ to the formation of precursor CH_{*n*}⁺ ions, electron-ion recombination reactions are studied in the He discharge flow, in which precursor CH_{*n*}⁺ ($n = 2-4$) ions are produced by the charge-transfer reactions of Ar⁺ or Kr⁺ with CH₄, and electrons are generated by the He(2^3S) Penning ionization of Ar or Kr. The intensity distribution of CH(A, B, C) and the rovibrational distributions of CH(A, B) are determined.

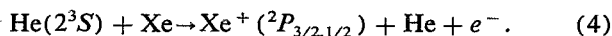
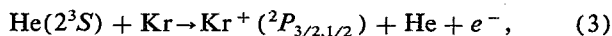
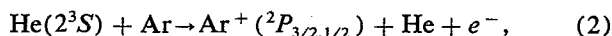
^{a)} Present address: Nakatsu Technical High School, Nakatsu, Oita 871, Japan.

^{b)} Present address: Department of Industrial Chemistry, Faculty of Engineering, Towa University, Chikushigaoka, Minami-ku, Fukuoka 815, Japan.

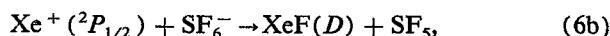
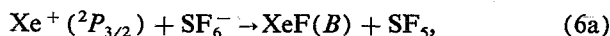
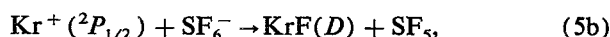
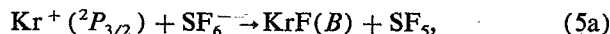
II. EXPERIMENTAL

The FA apparatus used in this study has been described in detail.⁵ Rare gas active species were generated by a microwave discharge of high purity rare gas in a discharge flow operated at 0.06–0.6 Torr (1 Torr = 133.3 Pa) for Ar and 0.04–0.07 Torr for Kr. The sample CH₄ gas was admixed with the discharge flow about 10 cm downstream from the center of the discharge. The partial pressure of CH₄ in the reaction zone was 2–20 mTorr. The active species involved in the Ar and Kr discharge flows were examined by observing optical emissions resulting from suitable reference reactions for metastable atoms and ions.^{6,7} It was found that Ar(³P_{2,0}), Ar⁺, and (Ar⁺)^{*} were involved in the Ar discharge flow, whereas Kr(³P₂), Kr⁺, and (Kr⁺)^{*} were present in the Kr flow under operating conditions. Metastable atoms were dominant active species at low rare gas pressures below 0.15 Torr for Ar and 0.05 Torr for Kr, while ionic species became significant at higher pressures. The contribution of ionic active species to the observed emissions was examined by using an ion-collector grid placed between the discharge section and the reaction zone. The efficiency of ion collection was found to be > 98% in all cases.

In addition to the conventional FA experiment described above, a new type of FA experiment was carried out for an optical spectroscopic study on electron–ion recombination reactions. The schematic diagram of the apparatus is shown in Fig. 1. Metastable He(2³S) atoms and He⁺ and He₂⁺ ions were generated by a microwave discharge of high purity He operated at 0.6–1.8 Torr. After trapping the ionic active species by using a pair of grids, the He(2³S) atoms flowed downstream past the first gas inlet from which a small amount of the Ar, Kr, or Xe gas was introduced. Ar⁺, Kr⁺, or Xe⁺ ions in the ground electronic states, ²P_{1/2} and ²P_{3/2}, and electrons were simultaneously produced by Penning ionization:



The rate constants for processes (2)–(4) have been measured as (7–9), (10–14), and (12–18) × 10^{−11} cm³ s^{−1}, respectively.⁸ The population ratios of ²P_{3/2}/²P_{1/2} in Kr⁺ and Xe⁺ were estimated by observing KrF(B–X, D–X) and XeF(B–X, D–X) excimer emissions produced from the following spin–orbit state selective reactions:⁹



where SF₆[−] was formed by an attachment of Penning electrons to SF₆:



It was found that most of the Kr⁺ and Xe⁺ ions in the reaction zone was in the lower ²P_{3/2} spin–orbit state. Such a technique could not be applied to the estimation of the ²P_{3/2}/²P_{1/2} ratio in Ar⁺, because ArF(B–X, D–X) emissions were heavily overlapped with each other.^{10,11} Since the energy interval between the two spin–orbit states in Ar⁺ (0.18 eV) is smaller than those in Kr⁺ (0.67 eV) and Xe⁺ (1.31 eV), the collisional relaxation from the upper ²P_{1/2} state to the lower ²P_{3/2} state in the He flow is expected to be much faster for Ar⁺. It is likely, therefore, most of Ar⁺ is also populated in the lower ²P_{3/2} state. The sample CH₄ gas was introduced into the discharge flow though the second inlet placed about 10 cm downstream from the first gas inlet. The partial pressure in the reaction zone was 10–50 mTorr for Ar, Kr, or Xe and 5–20 mTorr for CH₄.

A conical reaction flame observed around the CH₄ gas inlet was dispersed with a Jarrell Ash 1.0 m monochromator fitted with a 300 nm blazed grating and equipped with a cooled Hamamatsu Photonics R376 photomultiplier. The monochromator and the optical detection system were calibrated by using standard lamps.

III. RESULTS AND DISCUSSION

A. Excitation processes in the Ar and Kr afterglows

Figure 2 shows a typical emission spectrum obtained from the Ar afterglow reaction of CH₄. Besides the CH(A²Δ–X²Π_r, B²Σ[−]–X²Π_r) emission systems reported previously,^{1,2} a weak CH(C²Σ⁺–X²Π_r) emission system is identified around 315 nm. It was found that Ar⁺ and/or (Ar⁺)^{*} ions participated in the formation of CH(C) as well as CH(A, B), because the CH(C–X) band disappeared by ion trapping. The recombination energy of Ar⁺(²P_{3/2}) is 15.76 eV, and the available energies of (Ar⁺)^{*} are 16.41–20.27 eV for the (Ar⁺)^{*}→Ar⁺ excitation transfer and 17.87–22.19 eV for the (Ar⁺)^{*}→Ar^{*} charge transfer.⁶ Ta-

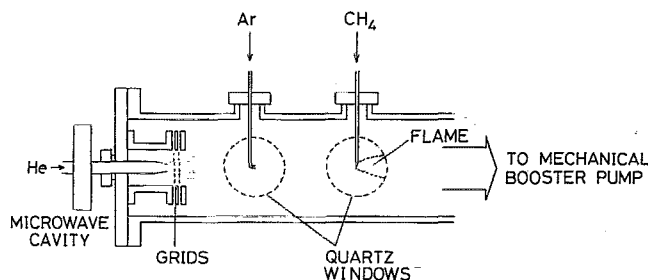


FIG. 1. The flowing afterglow apparatus for studying electron–ion recombination reactions.

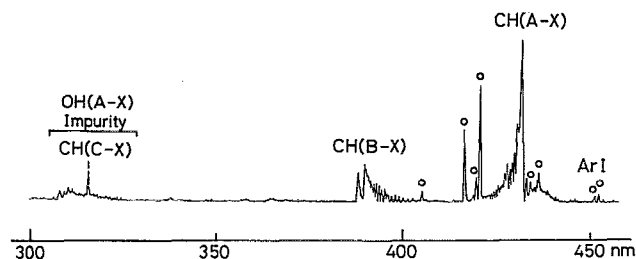
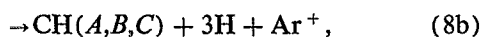
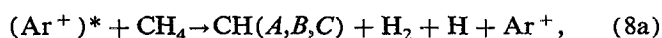


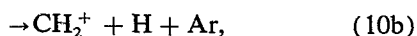
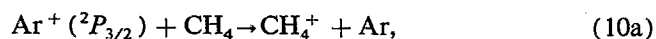
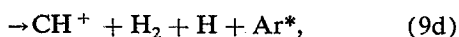
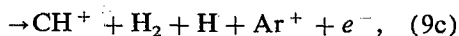
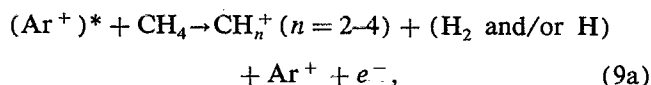
FIG. 2. Emission spectrum obtained from the Ar afterglow reaction of CH₄. The lines marked ○ are stray ArI lines. The optical resolution is 3.8 Å (FWHM).

ble I summarizes the calculated minimum energies for the formation of CH(*A,B,C*) and CH_{*n*}⁺ (*n* = 1–4) from CH₄. On the basis of energetics, the (Ar⁺)^{*} ions have sufficient energy to produce CH(*A,B,C*). However, CH(*A,B,C*) cannot be produced by the Ar⁺/CH₄ charge-transfer reaction. In our recent FA studies on the isovalent SiH₄ and GeH₄ molecules,^{7,14–16} we have found that both primary reactions of rare gas active species with the sample gases and secondary reactions involving ion–electron recombination take part in the production of neutral excited species. Therefore, the following primary and secondary processes are possible for the CH(*A,B,C*) production:

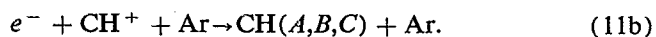
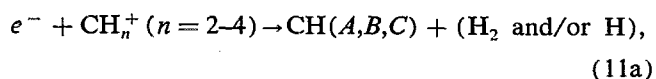
primary processes



secondary processes via electron–ion recombination



$$k_{10\text{a}} = 0.82, k_{10\text{b}} = 6.6, \text{ and } k_{10\text{c}} = 0.82 \text{ in } 10^{-10} \text{ cm}^3 \text{ s}^{-1} \text{ units},^{17}$$



If CH(*A,B,C*) are produced through the secondary pro-

TABLE I. Calculated minimum energies for the production of CH(*A,B,C*) and CH_{*n*}⁺ (*n* = 1–4) from CH₄.^a

| Products | Δ <i>H</i> ₀ ^o (eV) |
|--|---|
| CH ₄ → CH(<i>A</i> ² Δ) + H ₂ (<i>X</i> ¹ Σ _g ⁺) + H(<i>n</i> = 1) | 12.0 |
| → CH(<i>A</i> ² Δ) + 3H(<i>n</i> = 1) | 16.4 |
| → CH(<i>B</i> ² Σ [−]) + H ₂ (<i>X</i> ¹ Σ _g ⁺) + H(<i>n</i> = 1) | 12.3 |
| → CH(<i>B</i> ² Σ [−]) + 3H(<i>n</i> = 1) | 16.7 |
| → CH(<i>C</i> ² Σ ⁺) + H ₂ (<i>X</i> ¹ Σ _g ⁺) + H(<i>n</i> = 1) | 13.1 |
| → CH(<i>C</i> ² Σ ⁺) + 3H(<i>n</i> = 1) | 17.5 |
| → CH ₄ ⁺ + <i>e</i> [−] | 12.6 |
| → CH ₃ ⁺ + H(<i>n</i> = 1) + <i>e</i> [−] | 13.6 |
| → CH ₂ ⁺ + H ₂ (<i>X</i> ¹ Σ _g ⁺) + <i>e</i> [−] | 14.5 |
| → CH ₂ ⁺ + 2H(<i>n</i> = 1) + <i>e</i> [−] | 19.0 |
| → CH ⁺ (<i>X</i> ¹ Σ ⁺) + H ₂ (<i>X</i> ¹ Σ _g ⁺) + H(<i>n</i> = 1) + <i>e</i> [−] | 19.0 |

^aThe Δ*H*₀^o values are estimated from thermochemical and spectroscopic data in Refs. 12 and 13.

cesses, Ar⁺ as well as (Ar⁺)^{*} can take part in the reaction. Ar⁺ ions in process (10) are produced in the Ar discharge and through processes (8), (9a), and (9c). The effect of electron–ion recombination processes has been examined by adding SF₆ into the reaction zone. SF₆ not only attaches thermal electrons very rapidly (*k* = 2.2 × 10^{−7} cm³ s^{−1})¹⁸ but also quenches (Ar⁺)^{*}. Therefore, the reduction of [(Ar⁺)^{*}] by the addition of SF₆ should be corrected. In the present study, the decrease in [(Ar⁺)^{*}] by the SF₆ addition was corrected by observing Kr* lines resulting from the (Ar⁺)^{*}/Kr reaction:⁴

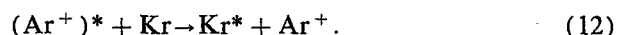


Figure 3 shows the dependence of CH(*A–X*) and Kr* emission intensities on the added SF₆ concentration at a constant CH₄ concentration. The Kr* line decreases with increasing the [SF₆]/[CH₄] ratio due to quenching of (Ar⁺)^{*} by SF₆. It should be noted that the CH(*A–X*) emission decreases more rapidly with [SF₆]/[CH₄] and almost disappears at a high [SF₆]/[CH₄] ratio of ~2. A similar tendency was found for CH(*B–X*) and CH(*C–X*). These results lead us to conclude that all of the CH(*A,B,C*) states are excited via electron–ion recombination processes (11).

When emission spectra of CH₄ in the Kr afterglow were observed at low Kr pressures below ~50 mTorr, where only Kr(³P₂) was involved in the discharge flow, no emission was detected. At high Kr pressures above ~60 mTorr, where Kr(³P₂), Kr⁺, and (Kr⁺)^{*} were present, the CH(*A–X*, *B–X*) emission systems were found as shown in Fig. 4. Outstanding features of the CH emission in the Kr afterglow in comparison with that in the Ar afterglow are that the *B–X* system becomes weak and the *C–X* system cannot be detected. When the ionic active species were trapped by using the ion-collector grid, the CH(*A–X*, *B–X*) emissions disappeared completely. This suggests that Kr⁺ and/or (Kr⁺)^{*} are responsible for the CH(*A,B*) production. The recombi-

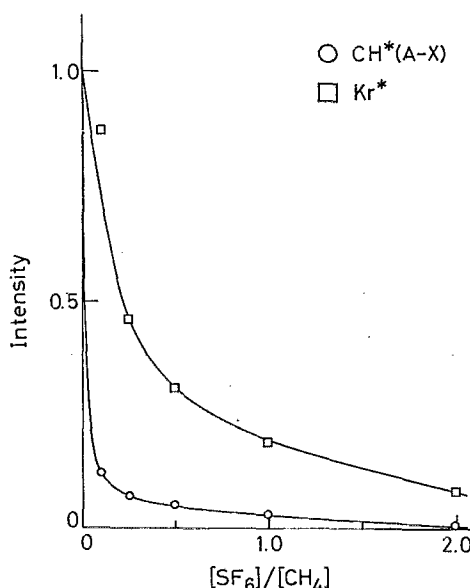


FIG. 3. The dependence of CH(*A–X*) and Kr* emission intensities on the [SF₆]/[CH₄] ratio.

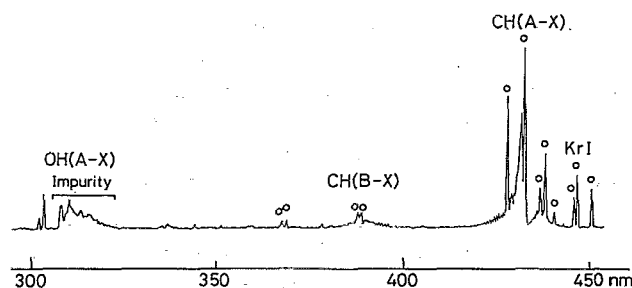
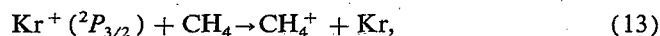
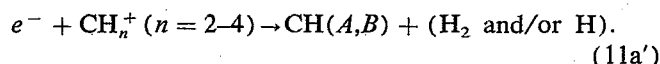
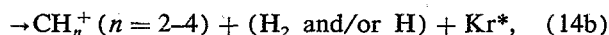
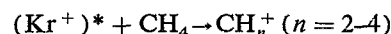


FIG. 4. Emission spectrum obtained from the Kr afterglow reaction of CH_4 . The lines marked \circ are stray KrI lines. The optical resolution is 4.7 \AA (FWHM).

nation energy of $\text{Kr}^+ (^2P_{3/2})$ is 14.00 eV, whereas the available energies of $(\text{Kr}^+)^*$ are 14.90–16.32 for the $(\text{Kr}^+)^* \rightarrow \text{Kr}^+$ excitation transfer and 15.90–18.32 eV for the $(\text{Kr}^+)^* \rightarrow \text{Kr}^*$ charge transfer.⁷ By addition of a small amount of SF_6 into the Kr discharge flow, the $\text{CH}(A-X, B-X)$ emissions disappeared as in the case of Ar discharge flow. On the basis of these findings and the energetics, all of $\text{CH}(A, B)$ are produced through the Kr^+/CH_4 and/or $(\text{Kr}^+)^*/\text{CH}_4$ reactions followed by electron-ion recombination processes:

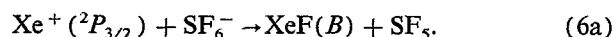
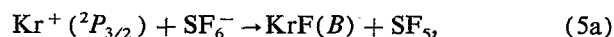
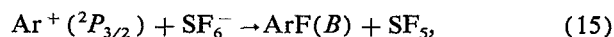


$$k_{13} = 1.0 \times 10^{-9} \text{ cm}^3 \text{ s}^{-1} \text{ (Ref. 19),}$$



B. Excitation processes in the He afterglow

In the Ar and Kr afterglow reactions of CH_4 , there are two possible ionic sources for the production of precursor ions of $\text{CH}(A, B)$: ground state ions (Ar^+ and Kr^+) and metastable ions [$(\text{Ar}^+)^*$ and $(\text{Kr}^+)^*$]. It was difficult to determine their relative contributions, because selective formation of one ionic species was not possible. In order to determine whether Ar^+ and Kr^+ participate in the reactions, emission spectra resulting from the Ar^+/CH_4 and Kr^+/CH_4 reactions followed by electron-ion recombination processes were observed by using the $\text{He}(2^3S)$ Penning ionization of Ar and Kr. The Xe^+/CH_4 reaction was also used for the production of precursor ions. The coexistence of Ar^+ , Kr^+ , or Xe^+ and electrons in the reaction zone was confirmed by observing $\text{ArF}(B-X)$, $\text{KrF}(B-X)$, and $\text{XeF}(B-X)$ resulting from the following ion-recombination reactions:^{9,10}



When the $\text{Ar}^+ (^2P_{3/2})/\text{CH}_4$ reaction was used for the production of precursor ions, strong $\text{CH}(A-X, B-X, C-X)$ emis-

sions were observed as shown in Fig. 5. On the other hand, no emission could be found, when precursor ions were formed by the $\text{Kr}^+ (^2P_{3/2})/\text{CH}_4$ and $\text{Xe}^+ (^2P_{3/2})/\text{CH}_4$ reactions. These results show that precursor ions are produced from the $\text{Ar}^+ (^2P_{3/2})/\text{CH}_4$ reaction, but the $\text{Kr}^+ (^2P_{3/2})/\text{CH}_4$ and $\text{Xe}^+ (^2P_{3/2})/\text{CH}_4$ reactions do not provide precursor ions. Thus, the $\text{Ar}^+ (^2P_{3/2})/\text{CH}_4$ reaction must take part in the $\text{CH}(A, B, C)$ formation in the Ar afterglow, while the $\text{Kr}^+ (^2P_{3/2})/\text{CH}_4$ reaction does not contribute to the $\text{CH}(A, B)$ formation in the Kr afterglow. The appearance of $\text{CH}(A-X, B-X)$ in the Kr afterglow leads us to conclude that all $\text{CH}(A-X, B-X)$ emissions result from the $(\text{Kr}^+)^*/\text{CH}_4$ reaction followed by electron-ion recombination processes. No direct evidence of the contribution of the $(\text{Ar}^+)^*/\text{CH}_4$ reaction to the $\text{CH}(A, B, C)$ production in the Ar afterglow was obtained. However, it may be reasonable to assume that the $(\text{Ar}^+)^*/\text{CH}_4$ reaction also participates in the $\text{CH}(A, B, C)$ production, because the available energies of $(\text{Ar}^+)^*$ are higher than those of $(\text{Kr}^+)^*$.

According to mass spectroscopic data, the Ar^+/CH_4 reaction at thermal energy provides CH_4^+ , CH_3^+ , and CH_2^+ ions with branching fractions of 0.10:0.80:0.10, respectively,¹⁷ whereas only parent CH_4^+ ions are formed by the $\text{Kr}^+ (^2P_{3/2})/\text{CH}_4$ and $\text{Xe}^+ (^2P_{3/2})/\text{CH}_4$ reactions.¹⁹ From the present results, dominant precursor ions for the $\text{CH}(A, B, C)$ production in the Ar afterglow reaction of CH_4 are not CH_4^+ but CH_3^+ and/or CH_2^+ .

Suzuki and Kuchitsu² concluded that $(\text{Ar}^+)^*$ is responsible for the $\text{CH}(A)$ production in the Ar afterglow reaction of CH_4 , because the Ar pressure dependence of $\text{CH}(A-X)$ was similar to that of Cl^* from $(\text{Ar}^+)^*/\text{HCl}$ ³ and Kr^* from $(\text{Ar}^+)^*/\text{Kr}$ and $\text{OCS}^+(\tilde{A}-\tilde{X})$ from Ar^+/OCS .^{20,21} The Ar pressure dependence of $\text{CH}(A-X)$ was similar to that of Kr^* in agreement with the result of Suzuki and Kuchitsu.² However, a significant discrepancy is found between the Ar pressure dependence of $\text{CH}(A-X)$ and $\text{OCS}^+(\tilde{A}-\tilde{X})$, though Ar^+ must contribute to the formation of $\text{CH}(A)$. This discrepancy is discussed below by a kinetic analysis of the reaction processes.

On the basis of the present results, $\text{CH}(A)$ probably results from secondary processes (9)–(11). Assuming a steady state condition for precursor $\text{CH}_n^+ (n = 1-4)$ ions, the production rate of $\text{CH}(A)$ is given by

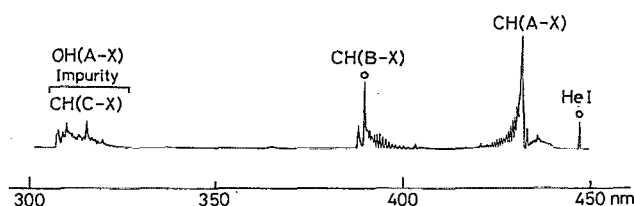


FIG. 5. $\text{CH}(A-X, B-X, C-X)$ emissions obtained through electron-ion recombination reactions in the He afterglow, where precursor ions are produced via $\text{Ar}^+ (^2P_{3/2})/\text{CH}_4$ reaction. The optical resolution is 2.9 \AA (FWHM).

$$\frac{d[\text{CH}(A)]}{dt} = (k_{9a} + k_{9b} + k_{9c} + k_{9d})[(\text{Ar}^+)^*][\text{CH}_4] + (k_{10b} + k_{10c})[\text{Ar}^+][\text{CH}_4]. \quad (17)$$

On the other hand, if a steady state condition is assumed for thermal electrons produced from reactions (9a) and (9c), the production rate of CH(*A*) is expressed by

$$\frac{d[\text{CH}(A)]}{dt} = (k_{9a} + k_{9c})[(\text{Ar}^+)^*][\text{CH}_4]. \quad (18)$$

Although the latter assumption explains the observed Ar pressure dependence of CH(*A,B*), the former assumption does not reproduce it without assuming $(k_{9a} + k_{9b} + k_{9c} + k_{9d})[(\text{Ar}^+)^*] \gg (k_{10b} + k_{10c})[\text{Ar}^+]$. It seems unlikely that this relation holds under the operating conditions, because Ar⁺ is an effective source of the production of precursor ions based upon the present study on the Ar⁺/CH₄ reaction in the He afterglow. Consequently, a strong correlation of CH(*A-X*) with (Ar⁺)^{*} in the Ar pressure dependence is probably attributable to the fact that the rate determining step for the CH(*A*) production is the formation of thermal electrons from processes (9a) and (9c).

C. Rovibrational distributions of CH(*A,B*)

Relative vibrational and rotational distributions of CH(*A,B*) produced by electron-ion recombination processes were determined by a computer simulation of CH(*A-X, B-X*). The band intensity (photons s⁻¹) of a transition from a (*v'*, *J'*) level to a (*v''*, *J''*) level is expressed as

$$I_{v'J',v''J''} \propto N_{v'J'} R_e^2(\bar{r}_{v'v''}) q_{v'v''}^3 \nu_{v'J',v''J''}^3 S_{J'J''} / (2J' + 1), \quad (19)$$

where $N_{v'J'}$ is the rotational population in a given vibrational level, $R_e(\bar{r}_{v'v''})$ the electronic transition moment, $q_{v'v''}$ the

Franck-Condon factor, $\nu_{v'J',v''J''}$ the transition frequency, and $S_{J'J''}$ is the rotational line strength. The electronic transition moment for CH(*A-X*) was assumed to be constant. The following RKR Franck-Condon factors calculated by using molecular constants tabulated in Ref. 13 were employed for the simulation of the $\Delta v = 0$ sequence of CH(*A-X*): $q_{0,0} = 0.9907$, $q_{1,1} = 0.9794$, and $q_{2,2} = 0.9793$. The rotational line strength $S_{J'J''}$ was deduced from the formula given by Kovács.²² A Gaussian slit function was convoluted into rotational lines to calculate the spectral envelope. Figures 6–8 show the observed and best fit spectra of the $\Delta v = 0$ sequence of CH(*A-X*) and the (0,0) band of CH(*B-X*) obtained assuming single or double Boltzmann rotational distributions for each *v'* level.

The vibrational and rotational distributions thus obtained are given in Table II together with the previous data by Suzuki and Kuchitsu² on CH(*A*) in the Ar afterglow reaction of CH₄. According to our recent optical spectroscopic study on the formation of CH(*A,B*) from the He(2³S)/CH₄ reaction,²³ the vibrational and rotational re-

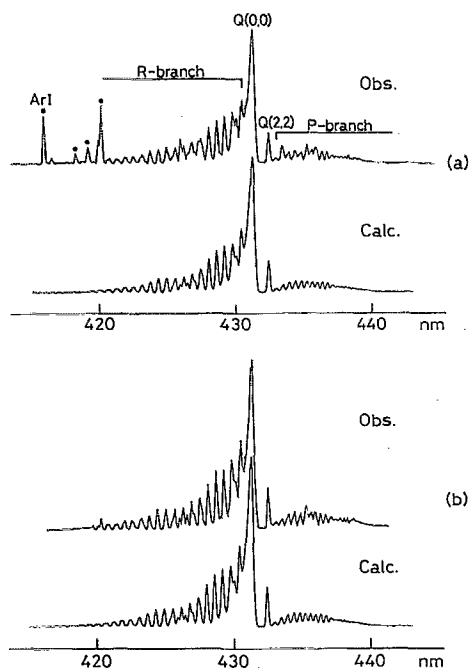


FIG. 6. The observed and calculated spectra of CH(*A*²Δ-*X*²Π_r) obtained from (a) electron-ion recombination reactions in the Ar afterglow and (b) e⁻/CH₂⁺ and/or e⁻/CH₃⁺ reactions in the He afterglow. The optical resolution is 1.8 Å (FWHM) for both (a) and (b).

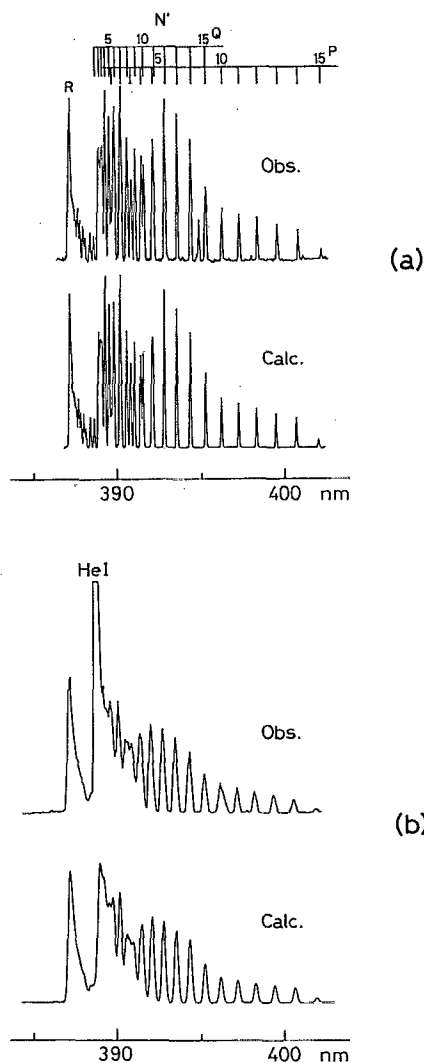


FIG. 7. The observed and calculated spectra of CH(*B*²Σ⁻-*X*²Π_r) obtained from (a) electron-ion recombination reactions in the Ar afterglow and (b) e⁻/CH₂⁺ and/or e⁻/CH₃⁺ reactions in the He afterglow. The optical resolution is 0.8 Å (FWHM) for (a) and 2.5 Å for (b).

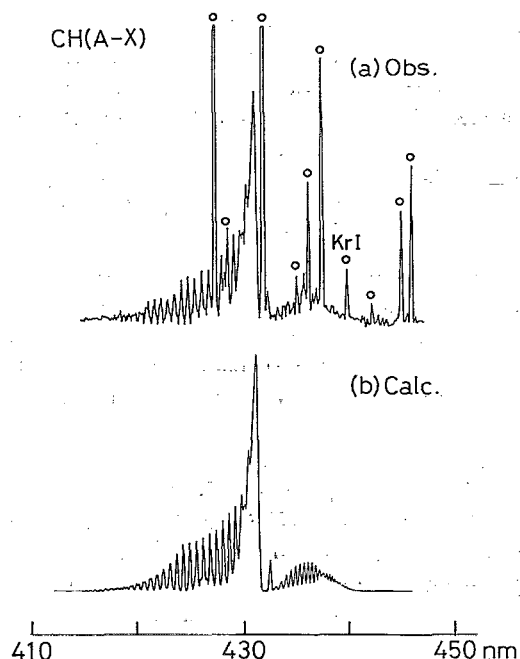


FIG. 8. The observed and calculated spectra of $\text{CH}(A^2\Delta-X^2\Pi_r)$ obtained from (a) electron-ion recombination reactions in the Kr afterglow. The optical resolution is 1.8 Å (FWHM).

laxation of $\text{CH}(A,B)$ by collisions with the buffer He gas is insignificant in the FA experiment during radiative lifetimes of ~ 0.53 and ~ 0.35 μs , respectively.²⁴ Therefore, the observed rovibrational distributions of $\text{CH}(A,B)$ are expected to reflect nascent populations. The rovibrational distribution of $\text{CH}(A)$ in the Ar afterglow obtained in the present study is close to that reported by Suzuki and Kuchitsu.² It should be noted that rovibrational distributions of $\text{CH}(A,B)$ in the Ar afterglow reaction of CH_4 are identical with those produced through the Ar^+/CH_4 reaction in the He afterglow. A similar resemblance was found for the relative inten-

sities of $\text{CH}(A,B,C)$. The $\text{CH}(A):\text{CH}(B):\text{CH}(C)$ ratios were measured to be 100:23:1, respectively, for both cases. On the basis of these findings, it is reasonable to assume that the Ar^+/CH_4 reaction plays a significant role for the $\text{CH}(A,B,C)$ production in the Ar afterglow or the $(\text{Ar}^+)^*/\text{CH}_4$ reaction gives the same precursor ions: e.g., CH_2^+ and/or CH_3^+ . The rotational distribution of $\text{CH}(A:v'=0)$ produced in the Ar afterglow and through the Ar^+/CH_4 reaction can be expressed by double Boltzmann distributions. This probably implies that two processes are involved in the formation of $\text{CH}(A)$. The rovibrational distribution of $\text{CH}(A)$ in the Kr afterglow is different from that in the Ar afterglow; $\text{CH}(A)$ in the Kr afterglow is less vibrationally excited but more rotationally excited than that in the Ar afterglow. A significant discrepancy is also found for the relative intensities of $\text{CH}(A,B,C)$. The $\text{CH}(A):\text{CH}(B):\text{CH}(C)$ ratios were measured as 100:10:0, respectively. Based upon these facts, dominant electron-ion recombination processes leading to $\text{CH}(A,B)$ in the Kr afterglow are different from those in the Ar afterglow.

The average vibrational and rotational energies of $\text{CH}(A,B)$ were evaluated from the rovibrational distributions by using the relations:

$$\langle E_v \rangle = \sum_v N_v E_v / \sum_v N_v, \quad (20)$$

$$\langle E_J \rangle = \sum_v \sum_J N_{vJ} E_J / \sum_v \sum_J N_{vJ}, \quad (21)$$

where E_v and E_J are the vibrational and rotational energies, respectively. The $\langle E_v \rangle$ and $\langle E_J \rangle$ values are summarized in Table III. The $\langle E_J \rangle$ values are larger than the $\langle E_v \rangle$ values in all cases. The energetics of possible electron-ion recombination processes through the Ar^+/CH_4 reaction in the He afterglow are as follows:

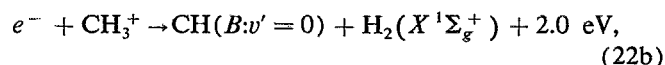
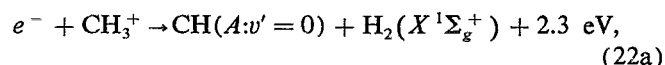


TABLE II. The rovibrational distributions of $\text{CH}(A^2\Delta, B^2\Sigma^-)$ produced from electron-ion recombination processes in the flowing afterglow.

| | $\text{Ar}^+, (\text{Ar}^+)^*/\text{CH}_4^a$ $\text{CH}(A^2\Delta)$ | | | | $\text{Ar}^+/\text{CH}_4^b$ $\text{CH}(A^2\Delta)$ | | $(\text{Kr}^+)^*/\text{CH}_4^c$ $\text{CH}(A^2\Delta)$ | |
|--------------------------|--|---------------------------------|---|-----------------|---|---------------------------------|---|----------------|
| | This work N_v | T_r (K) | Suzuki and Kuchitsu ^d N_v | T_r (K) | This work N_v | T_r (K) | This work N_v | T_r (K) |
| $v'=0$ | 72 ± 8 28 ± 8 | 3200 ± 700 500 ± 100 | 100 | 3000 ± 1500 | 72 ± 8 28 ± 8 | 3200 ± 700 500 ± 100 | 100 | 2900 ± 300 |
| $v'=1$ | 40 ± 5 | 1700 ± 400 | 56 | 1700 ± 400 | 40 ± 5 | 1700 ± 400 | 25 ± 5 | 2100 ± 300 |
| $v'=2$ | 10 ± 1 | 1200 ± 300 | 10 | 1000 | 10 ± 1 | 1200 ± 300 | 4 ± 1 | 1500 ± 900 |
| $\text{CH}(B^2\Sigma^-)$ | | | | | | | | |
| | This work N_v | T_r (K) | | | | | | |
| $v'=0$ | 65 ± 4 35 ± 4 | 3200 ± 1100 650 ± 50 | $\text{CH}(B^2\Sigma^-)$ | | | | | |
| | This work N_v | T_r (K) | | | | | | |
| $v'=0$ | 65 ± 4 35 ± 4 | 3800 ± 1100 650 ± 50 | | | | | | |

^a Measured in the Ar afterglow.

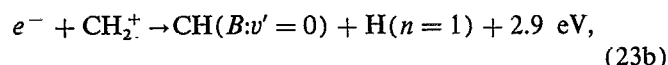
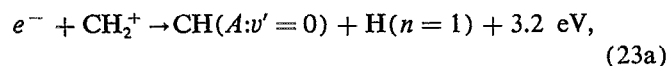
^b Measured in the He afterglow (see the text).

^c Measured in the Kr afterglow.

^d Reference 2.

TABLE III. Average vibrational and rotational energies deposited into the CH(*A,B*).

| Energies (eV) | Ar ⁺ , (Ar ⁺)* / CH ₄ ^a | Processes Ar ⁺ / CH ₄ ^b | (Kr ⁺)* / CH ₄ ^c |
|-----------------------|--|---|--|
| | CH(<i>A</i> ² Δ) | CH(<i>A</i> ² Δ) | CH(<i>A</i> ² Δ) |
| $\langle E_v \rangle$ | 0.13 | 0.13 | 0.086 |
| $\langle E_r \rangle$ | 0.19 | 0.19 | 0.23 |
| | CH(<i>B</i> ² Σ ⁻) | CH(<i>B</i> ² Σ ⁻) | |
| $\langle E_v \rangle$ | 0 | 0 | |
| $\langle E_r \rangle$ | 0.23 | 0.23 | |

^a Measured in the Ar afterglow.^b Measured in the He afterglow (see the text).^c Measured in the Kr afterglow.

Assuming that either process (22) or (23) dominates the reaction, the fractions of excess energies deposited into the vibrational and rotational energies of CH(*A,B*) are estimated to be

$$\langle f_v \rangle = 0.057 \text{ and } \langle f_r \rangle = 0.083 \text{ for process (22a),}$$

$$\langle f_v \rangle = 0 \text{ and } \langle f_r \rangle = 0.12 \text{ for process (22b),}$$

$$\langle f_v \rangle = 0.041 \text{ and } \langle f_r \rangle = 0.059 \text{ for process (23a),}$$

$$\langle f_v \rangle = 0 \text{ and } \langle f_r \rangle = 0.079 \text{ for process (23b).}$$

Only 8%–14% of the excess energies is released as the vibrational and rotational energies of CH(*A,B*), indicating that most of the excess energies is deposited as relative translational energy of fragments. The high $\langle f_r \rangle$ value implies that CH(*A,B*) are formed through highly repulsive CH₃⁺⁺ and/or CH₂⁺⁺ precursor states in processes (22) and (23).

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